

Search Notes**Application/Control No.**

10/085,145

Examiner

Tan Dean D. Nguyen

Applicant(s)/Patent under Reexamination

MEISER ET AL.

Art Unit

3629

SEARCHED

Class	Subclass	Date	Examiner
705	1	6/06	DN
	7		
	8		
	9		
	10		
	14		
	26		
709	202		
	205		
	217	✓	✓
	229		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
US	6/06	DN
Pat PG Pub Foreign	✓	✓
EP JPO Korean	✓	✓